

**Search Notes**

Application/Control No.

10/779,779

Examiner

W. Patty Chen

Applicant(s)/Patent under  
Reexamination

NIIYA, HIROTAKE

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
reviewed previously cited references	12/29/2006	WPC
citations search of tagged reference	12/29/2006	WPC